Statistical tools for impact studies at EIC

Rabah Abdul Khalek, 28/04/2020 **EIC YR**

Collaborating with:

Valerio Bertone

Timothy Hobbs

Daniel Pitonyak

Alexei Produkin

Nobuo Sato

Motivation

- Comparing the impact of different EIC detector configurations on PDFs from vertex-level generated events
- Giving experimentalists a (hopefully reliable) tool to efficiently gauge the impact of different detector configurations.
- Providing an alternative for fitting PDFs with many configuration settings

1. Consider a feature to study e.g Impact on strangeness of unpolarised PDFs

2. Define two extreme cases
Construct two PDF sets with two
Extreme cases of strange (max and min)
According to phenomenology

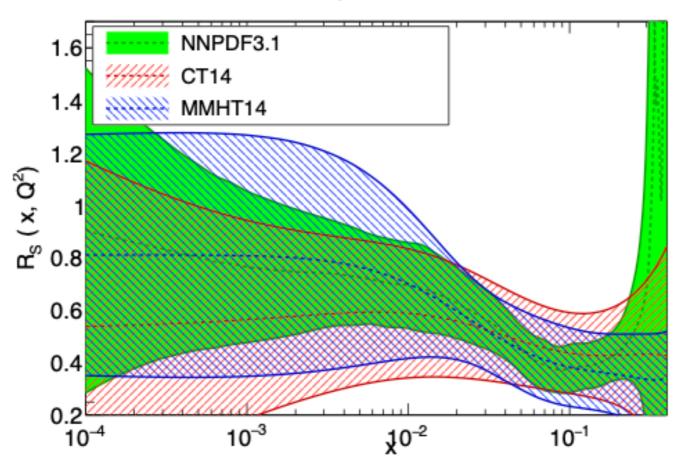
3. Compute SF from the extreme PDFs in LHAPDF grids format

4. Generate 2 MC samples reduced cross sections from max and min cases

5. Perform statistical test on the samples to gauge the sigma-level significance of discrimination in bin of (x,Q2)

1. Consider a feature to study e.g Impact on strangeness of unpolarised PDFs

NNLO, Q=1.38 GeV

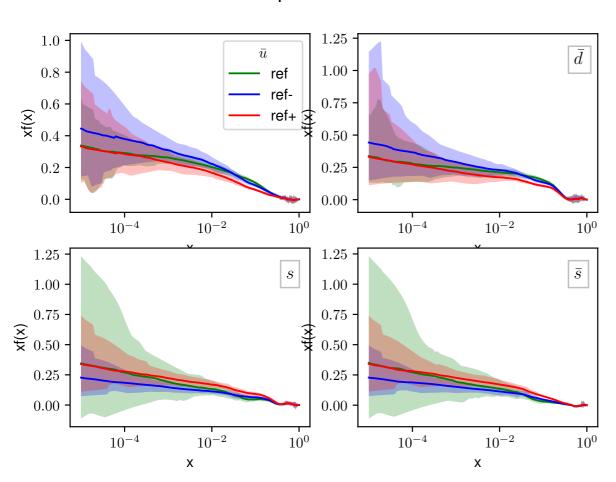


$$R_s = \frac{s + \bar{s}}{\bar{u} + \bar{d}} \simeq [0.5, 1],$$

2. Define two extreme cases

Construct two PDF sets with two
Extreme cases of strange (max and min)
According to phenomenology

NNPDF31_nnlo_pch_as_0118 at Q = 1 GeV

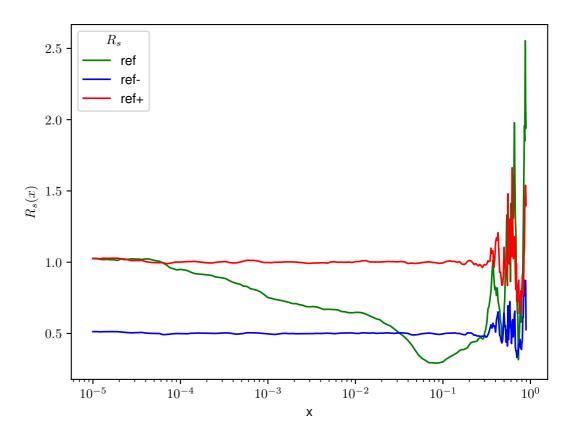


$$s(x) \to s(x) + \kappa(x)$$
, $\bar{s}(x) \to \bar{s}(x) + \kappa(x)$,

and:

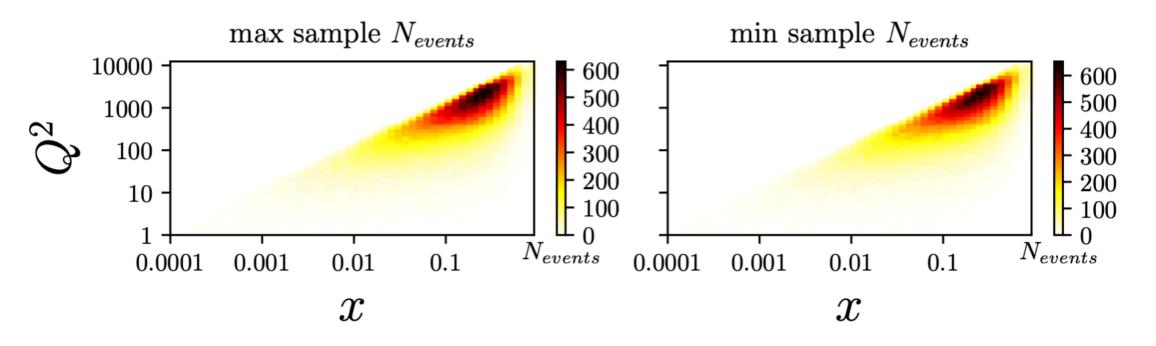
$$\bar{u}(x) \to \bar{u}(x) - \kappa(x)$$
, $\bar{d}(x) \to \bar{d}(x) - \kappa(x)$.

NNPDF31_nnlo_pch_as_0118 $R_s=rac{s+ar{s}}{u+ar{u}}$ at Q = 1 GeV



Such that $0.5 \le R_s \le 1$

- 3. Compute SF from the extreme PDFs in LHAPDF grids format
- 4. Generate 2 MC samples reduced cross sections from max and min cases



$$N_x = 50, N_{Q^2} = 50$$

 $N_{events} = 100k$
 $\sqrt{s} = 140.70 \text{ GeV}$
 $W^2 > 10, Q^2 > 1$

5. Perform statistical test on the samples

to gauge the sigma-level significance of discrimination in bin of (x,Q2)

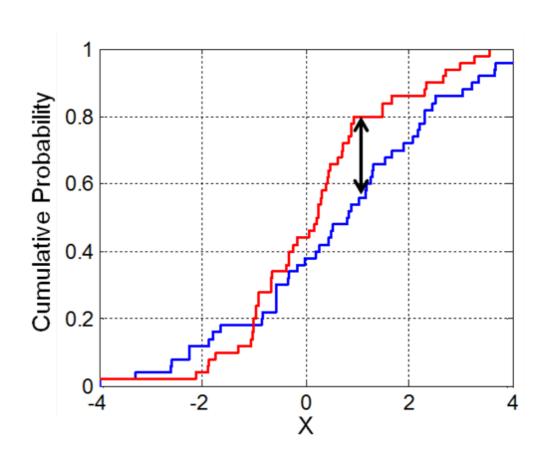
For example: Kolmogorov-Smirnov Test

$$D_{n,m} = \sup_x |F_{1,n}(x) - F_{2,m}(x)|$$

For large samples, the null hypothesis is rejected at level α if:

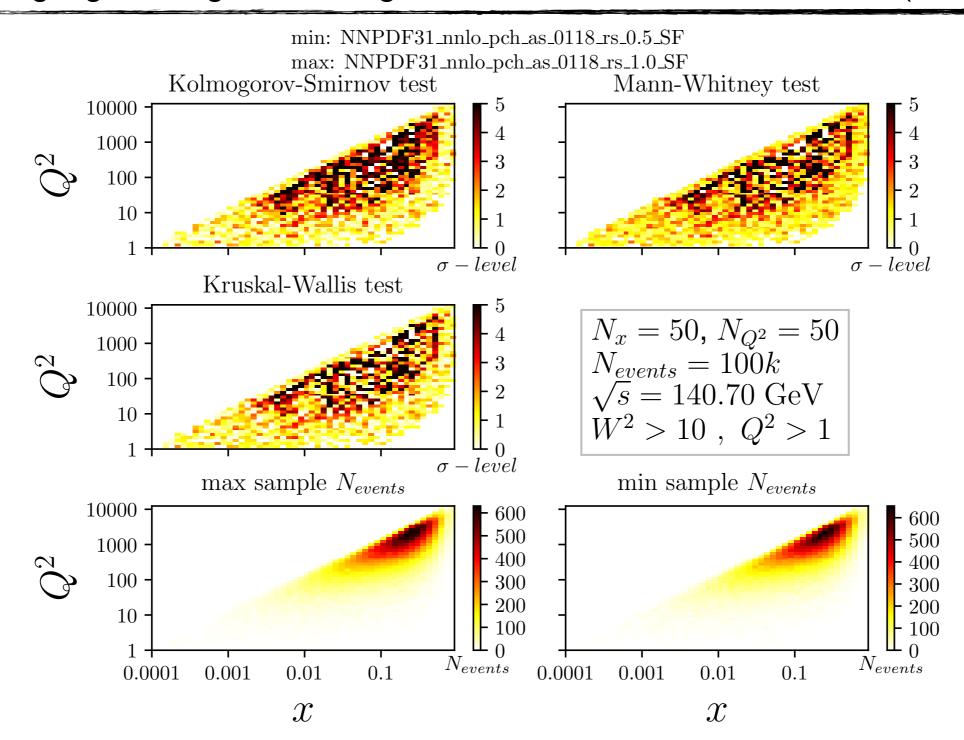
$$D_{n,m} > c(lpha) \sqrt{rac{n+m}{n\cdot m}}.$$

Where a (p-value) is the probability of detecting a difference under the assumptions of the null hypothesis (that the two samples are drawn from the same distribution).



5. Perform statistical test on the samples

to gauge the sigma-level significance of discrimination in bin of (x,Q2)



Summary

 We still need to perform a background events substraction, and add detector effects to our cross sections:

$$\sigma(x, Q^2 | H) = [\sigma_S(x, Q^2 | H) - \sigma_B(x, Q^2 | H)] \pi(x, Q^2 | H, \mathcal{L}, RC, detector)$$

- 1. It is at this level that our exercise would start to be useful, comparing the change of discrimination before and after adding detector effects.
- 2. At this point, we'll be also able to compare also between different configuration settings.
- Currently working on implementing the t-test as performed in https://arxiv.org/pdf/1501.03156.pdf